

Edge-TCT studies of non-irradiated HVCMOS sensors

Thursday 12 June 2014 11:20 (20 minutes)

A HVCMOS sensor (HVCMOS2FEI4) was investigated before the irradiation with Edge-TCT. Key properties of the charge collection in p substrate were determined by different analysis methods. Good agreement between the measured and given substrate resistivity was found. The measurements revealed that the major contribution to the measured charge comes from the movement of carriers by diffusion and only a fraction from the drift. The drift component increases with applied bias voltage and reaches around 30% at 60V. Charge collection measurements from Edge-TCT were also compared to 90Sr measurements.

Author: KRAMBERGER, Gregor (Jozef Stefan Institute (SI))

Co-authors: LA ROSA, Alessandro (Universite de Geneve (CH)); ROZANOV, Alexandre (CPPM, Aix-Marseille Université, CNRS/IN2P3 (FR)); Dr BLUE, Andrew (University of Glasgow); MIUCCI, Antonio (Universite de Geneve (CH)); QUADT, Arnulf (Georg-August-Universitaet Goettingen (DE)); RISTIC, Branislav (Universite de Geneve (CH)); KREIDL, Christian (Heidelberg University); BUTTAR, Craig (University of Glasgow (GB)); HYND, Daniel (University of Glasgow); MUENSTERMANN, Daniel (Universite de Geneve (CH)); FERRERE, Didier (Universite de Geneve (CH)); HUEGGING, Fabian (University of Bonn); BOMPARD, Frederic (Centre National de la Recherche Scientifique (FR)); IACOBUCCI, Giuseppe (Universite de Geneve (CH)); KRUEGER, Hans (University of Bonn); PERNEGGER, Heinz (CERN); MANDIC, Igor (Jozef Stefan Institute (SI)); PERIC, Ivan (Ruprecht-Karls-Universitaet Heidelberg (DE)); WEINGARTEN, Jens (Georg-August-Universitaet Goettingen (DE)); GROSSE-KNETTER, Joern (Georg-August-Universitaet Goettingen (DE)); RIEGER, Julia Katharina (Georg-August-Universitaet Goettingen (DE)); BACKHAUS, Malte (CERN); CAPEANS GARRIDO, Mar (CERN); MIKUZ, Marko (Jozef Stefan Institute (SI)); Dr ZAVRTANIK, Marko (Jozef Stefan Institute (SI)); BARBERO, Marlon B. (CPPM - CNRS/IN2P3 / Aix-Marseille Université (FR)); NESSI, Marzio (CERN); GEORGE, Matthias Alexander (Georg-August-Universitaet Goettingen (DE)); GARCIA-SCIVERES, Mauricio (Lawrence Berkeley National Lab. (US)); WERMES, Norbert (Universitaet Bonn (DE)); BREUGNON, Patrick (Centre National de la Recherche Scientifique (FR)); PANGAUD, Patrick (Centre National de la Recherche Scientifique (FR)); BATES, Richard (University of Glasgow (GB)); GONZALEZ SEVILLA, Sergio (Universite de Geneve (CH)); FEIGL, Simon (CERN); OBERMANN, Theresa (Universitaet Bonn (DE)); HEMPEREK, Tomasz (Universitaet Bonn (DE)); CINDRO, Vladimir (Jozef Stefan Institute (SI))

Presenter: KRAMBERGER, Gregor (Jozef Stefan Institute (SI))

Session Classification: Session 3 - TCAD simulations